Application/Control No.	Applicant(s)/Patent under Reexamination
10/647,767	DIORIO ET AL.
Examiner	Art Unit
Jinhee J. Lee_	2174

SEARCHED					
Class	Subclass	Date	Examiner		
715	854,742	12/9/2006	LEE		
709	223	71	17		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
715,709	as above	12/9/2006	LEE			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East text search attached	12/9/2006	LEE		
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